

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/748,892	HU ET AL.	
	<b>Examiner</b> Anthony Weier	<b>Art Unit</b> 1761	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
426	422, 423		
	295, 592		
	330.4	11/21/2006	AW